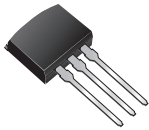


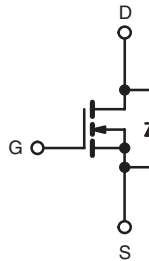
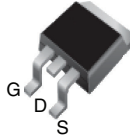
Power MOSFET

| PRODUCT SUMMARY | |
|---------------------------|-----------------------------|
| V_{DS} (V) | 500 |
| $R_{DS(on)}$ (Ω) | $V_{GS} = 10\text{ V}$ 0.85 |
| Q_g (Max.) (nC) | 38 |
| Q_{gs} (nC) | 9.0 |
| Q_{gd} (nC) | 18 |
| Configuration | Single |

I²PAK (TO-262)



D²PAK (TO-263)



N-Channel MOSFET

FEATURES

- Low Gate Charge Q_g Results in Simple Drive Requirement
- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Effective C_{OSS} Specified
- Lead (Pb)-free Available



RoHS*
COMPLIANT

APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply
- High Speed Power Switching

TYPICAL SMPS TOPOLOGIES

- Two Transistor Forward
- Half Bridge
- Full Bridge

| ORDERING INFORMATION | | | | |
|----------------------|-----------------------------|-----------------------------|-----------------------------|-----------------------------|
| Package | D ² PAK (TO-263) | D ² PAK (TO-263) | D ² PAK (TO-263) | I ² PAK (TO-262) |
| Lead (Pb)-free | IRF840ASPbF | IRF840ASTRLPbF ^a | IRF840ASTRRPbF ^a | IRF840ALPbF |
| | SiHF840AS-E3 | SiHF840ASTL-E3 ^a | SiHF840ASTR-E3 ^a | SiHF840AL-E3 |
| SnPb | IRF840AS | IRF840ASTL ^a | IRF840ASTRR ^a | IRF840AL |
| | SiHF840AS | SiHF840ASTL ^a | SiHF840ASTR ^a | SiHF840AL |

Note

a. See device orientation.

| ABSOLUTE MAXIMUM RATINGS $T_C = 25\text{ }^\circ\text{C}$, unless otherwise noted | | | | |
|--|----------------------------------|-----------------------------------|------------------|---------------------|
| PARAMETER | SYMBOL | | LIMIT | UNIT |
| Drain-Source Voltage | V_{DS} | | 500 | V |
| Gate-Source Voltage | V_{GS} | | ± 30 | |
| Continuous Drain Current | V_{GS} at 10 V | $T_C = 25\text{ }^\circ\text{C}$ | 8.0 | A |
| | | $T_C = 100\text{ }^\circ\text{C}$ | 5.1 | |
| Pulsed Drain Current ^a | I_{DM} | | 32 | |
| Linear Derating Factor | | | 1.0 | W/ $^\circ\text{C}$ |
| Single Pulse Avalanche Energy ^b | E_{AS} | | 510 | mJ |
| Repetitive Avalanche Current ^a | I_{AR} | | 8.0 | A |
| Repetitive Avalanche Energy ^a | E_{AR} | | 13 | mJ |
| Maximum Power Dissipation | $T_C = 25\text{ }^\circ\text{C}$ | | 125 | W |
| | $T_A = 25\text{ }^\circ\text{C}$ | | 3.1 | |
| Peak Diode Recovery dV/dt ^{c, e} | dV/dt | | 5.0 | V/ns |
| Operating Junction and Storage Temperature Range | T_J, T_{stg} | | - 55 to + 150 | $^\circ\text{C}$ |
| Soldering Temperature | for 10 s | | 300 ^d | |

Notes


- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- Starting $T_J = 25\text{ }^\circ\text{C}$, $L = 16\text{ mH}$, $R_G = 25\text{ }^\circ\Omega$, $I_{AS} = 8.0\text{ A}$ (see fig. 12).
- $I_{SD} \leq 8.0\text{ A}$, $dI/dt \leq 100\text{ A}/\mu\text{s}$, $V_{DD} \leq V_{DS}$, $T_J \leq 150\text{ }^\circ\text{C}$.
- 1.6 mm from case.
- Uses IRF840A/SiH840A data and test conditions.

* Pb containing terminations are not RoHS compliant, exemptions may apply

| THERMAL RESISTANCE RATINGS | | | | | |
|--|------------|------|------|------|------|
| PARAMETER | SYMBOL | MIN. | TYP. | MAX. | UNIT |
| Maximum Junction-to-Ambient (PCB Mount) ^a | R_{thJA} | - | - | 40 | °C/W |
| Maximum Junction-to-Case (Drain) | R_{thJC} | - | - | 1.0 | |

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

| SPECIFICATIONS $T_J = 25\text{ }^\circ\text{C}$, unless otherwise noted | | | | | | | |
|--|-----------------------|--|---|------|------|-----------|---------------|
| PARAMETER | SYMBOL | TEST CONDITIONS | | MIN. | TYP. | MAX. | UNIT |
| Static | | | | | | | |
| Drain-Source Breakdown Voltage | V_{DS} | $V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$ | | 500 | - | - | V |
| V_{DS} Temperature Coefficient | $\Delta V_{DS}/T_J$ | Reference to $25\text{ }^\circ\text{C}$, $I_D = 1\text{ mA}^d$ | | - | 0.58 | - | V/°C |
| Gate-Source Threshold Voltage | $V_{GS(th)}$ | $V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$ | | 2.0 | - | 4.0 | V |
| Gate-Source Leakage | I_{GSS} | $V_{GS} = \pm 30\text{ V}$ | | - | - | ± 100 | nA |
| Zero Gate Voltage Drain Current | I_{DSS} | $V_{DS} = 500\text{ V}, V_{GS} = 0\text{ V}$ | | - | - | 25 | μA |
| | | $V_{DS} = 400\text{ V}, V_{GS} = 0\text{ V}, T_J = 125\text{ }^\circ\text{C}$ | | - | - | 250 | |
| Drain-Source On-State Resistance | $R_{DS(on)}$ | $V_{GS} = 10\text{ V}$ | $I_D = 4.8\text{ A}^b$ | - | - | 0.85 | Ω |
| Forward Transconductance | g_{fs} | $V_{DS} = 50\text{ V}, I_D = 4.8\text{ A}$ | | 3.7 | - | - | S |
| Dynamic | | | | | | | |
| Input Capacitance | C_{iss} | $V_{GS} = 0\text{ V}, V_{DS} = 25\text{ V}, f = 1.0\text{ MHz}$, see fig. 5 | | - | 1018 | - | pF |
| Output Capacitance | C_{oss} | | | - | 155 | - | |
| Reverse Transfer Capacitance | C_{rss} | | | - | 8.0 | - | |
| Output Capacitance | C_{oss} | $V_{GS} = 0\text{ V}$ | $V_{DS} = 1.0\text{ V}, f = 1.0\text{ MHz}$ | 1490 | - | - | |
| Output Capacitance | C_{oss} | | $V_{DS} = 400\text{ V}, f = 1.0\text{ MHz}$ | 42 | - | - | |
| Effective Output Capacitance | $C_{oss\text{ eff.}}$ | | $V_{DS} = 0\text{ V to } 480\text{ V}^{c, d}$ | 56 | - | - | |
| Total Gate Charge | Q_g | $V_{GS} = 10\text{ V}$ | $I_D = 8.0\text{ A}, V_{DS} = 400\text{ V}$, see fig. 6 and 13 ^{b, d} | - | - | 38 | nC |
| Gate-Source Charge | Q_{gs} | | | - | - | 9.0 | |
| Gate-Drain Charge | Q_{gd} | | | - | - | 18 | |
| Turn-On Delay Time | $t_{d(on)}$ | $V_{DD} = 250\text{ V}, I_D = 8.0\text{ A}, R_G = 9.1\text{ }\Omega, R_D = 31\text{ }\Omega$, see fig. 10 ^{b, d} | | - | 11 | - | ns |
| Rise Time | t_r | | | - | 23 | - | |
| Turn-Off Delay Time | $t_{d(off)}$ | | | - | 26 | - | |
| Fall Time | t_f | | | - | 19 | - | |
| Drain-Source Body Diode Characteristics | | | | | | | |
| Continuous Source-Drain Diode Current | I_S | MOSFET symbol showing the integral reverse p-n junction diode  | | - | - | 8.0 | A |
| Pulsed Diode Forward Current ^a | I_{SM} | | | - | - | 32 | |
| Body Diode Voltage | V_{SD} | $T_J = 25\text{ }^\circ\text{C}, I_S = 8.0\text{ A}, V_{GS} = 0\text{ V}^b$ | | - | - | 2.0 | V |
| Body Diode Reverse Recovery Time | t_{rr} | $T_J = 25\text{ }^\circ\text{C}, I_F = 8.0\text{ A}, di/dt = 100\text{ A}/\mu\text{s}^b$ | | - | 422 | 633 | ns |
| Body Diode Reverse Recovery Charge | Q_{rr} | | | - | 2.0 | 3.0 | μC |
| Forward Turn-On Time | t_{on} | Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D) | | | | | |

Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- Pulse width $\leq 300\text{ }\mu\text{s}$; duty cycle $\leq 2\%$.
- $C_{oss\text{ eff.}}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DS} .
- Uses IRF840A/SiHF840A data and test conditions

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

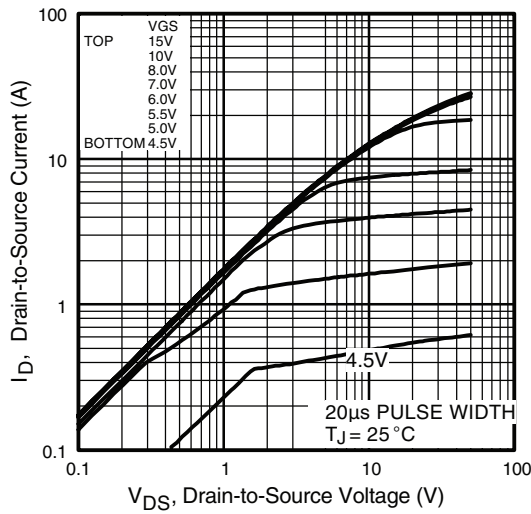


Fig. 1 - Typical Output Characteristics

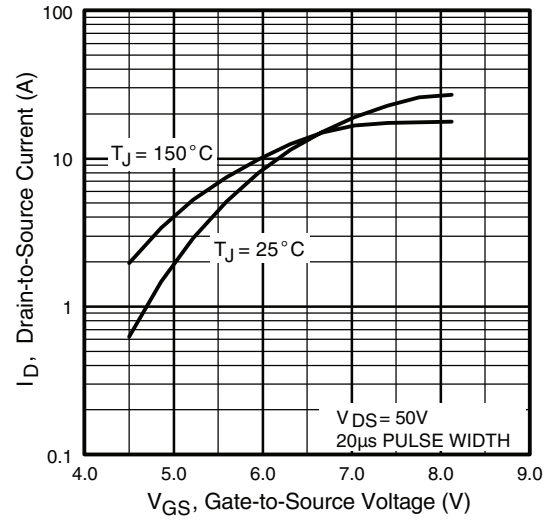


Fig. 3 - Typical Transfer Characteristics

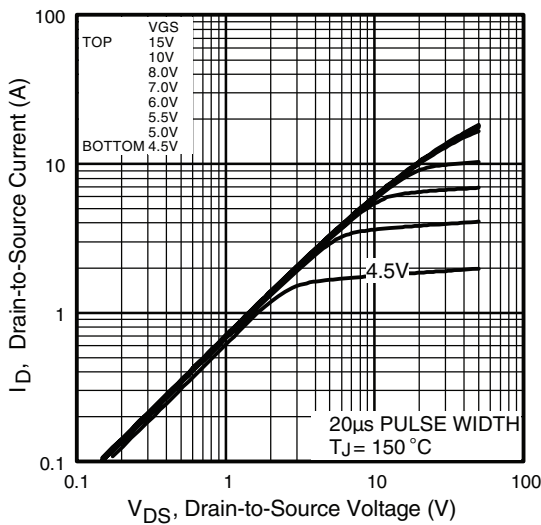


Fig. 2 - Typical Output Characteristics

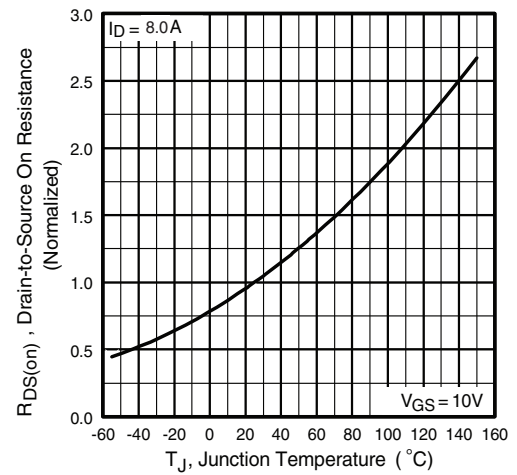


Fig. 4 - Normalized On-Resistance vs. Temperature

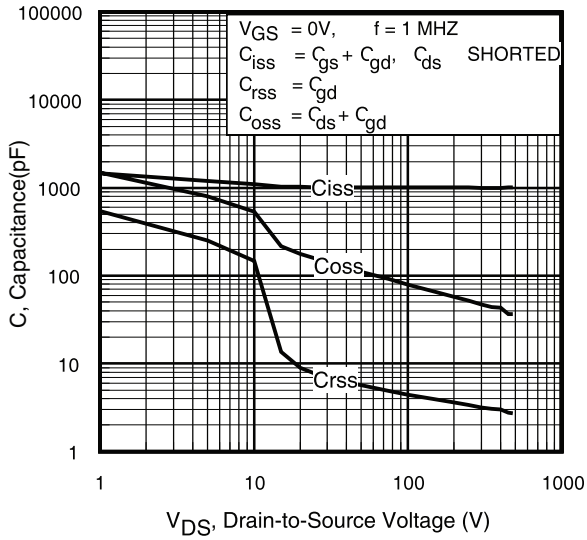


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

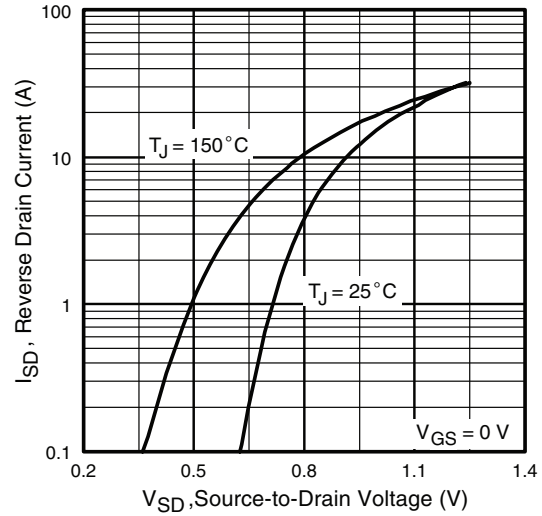


Fig. 7 - Typical Source-Drain Diode Forward Voltage

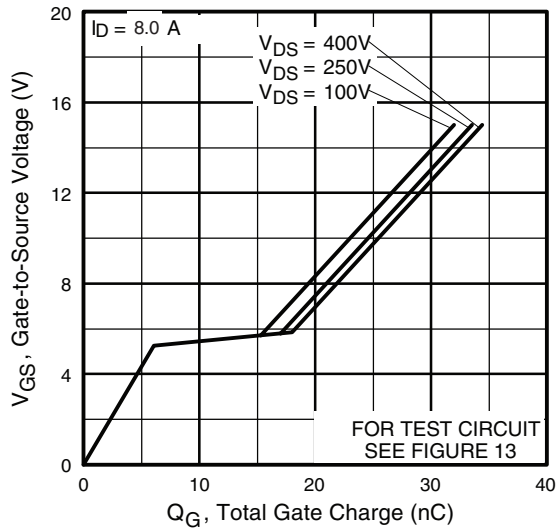


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

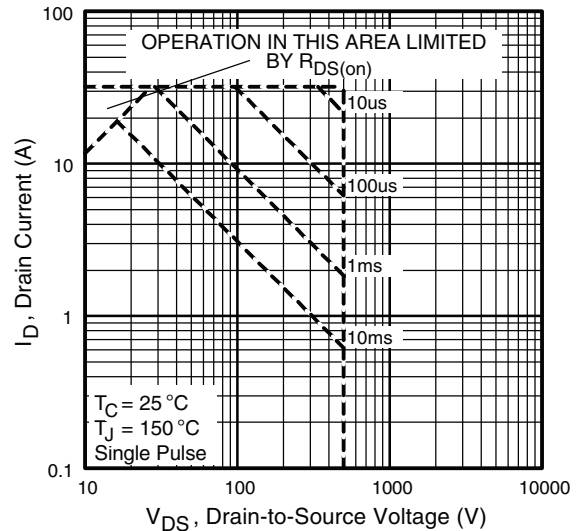


Fig. 8 - Maximum Safe Operating Area

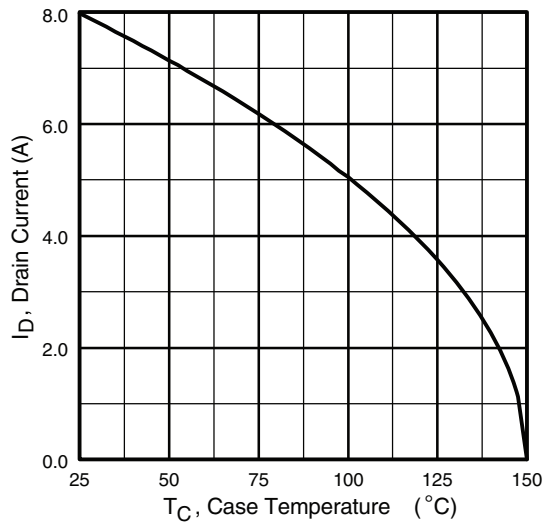


Fig. 9 - Maximum Drain Current vs. Case Temperature

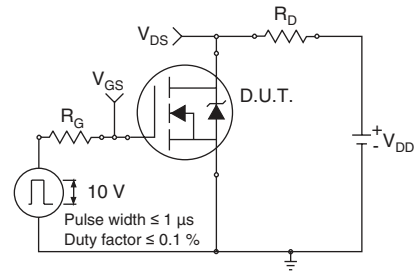


Fig. 10a - Switching Time Test Circuit

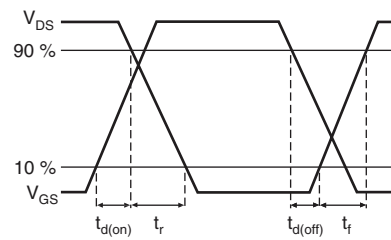


Fig. 10b - Switching Time Waveforms

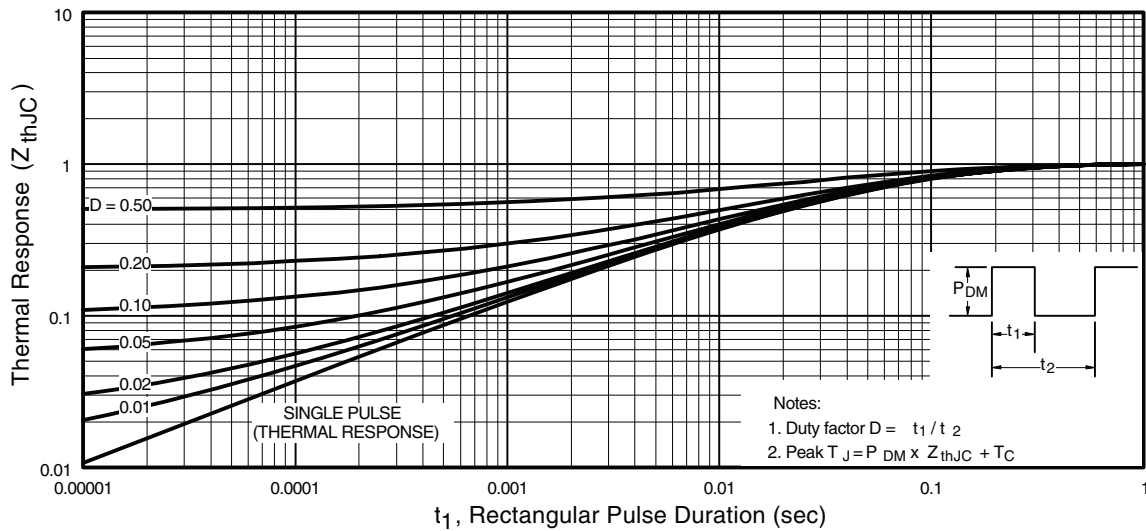


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

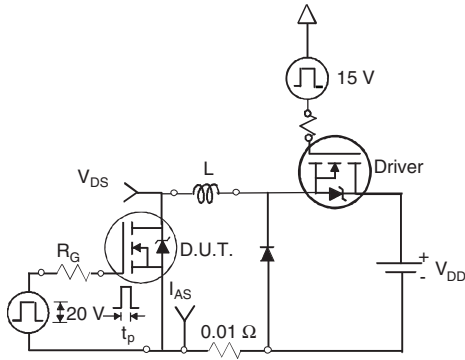


Fig. 12a - Unclamped Inductive Test Circuit

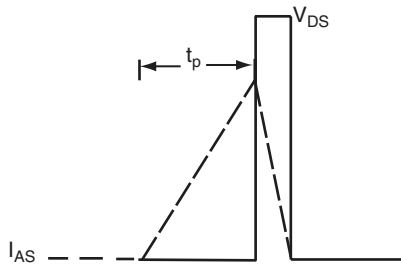


Fig. 12b - Unclamped Inductive Waveforms

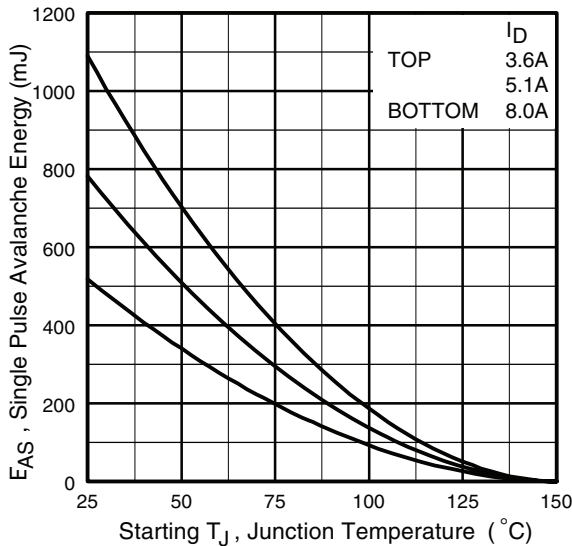


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

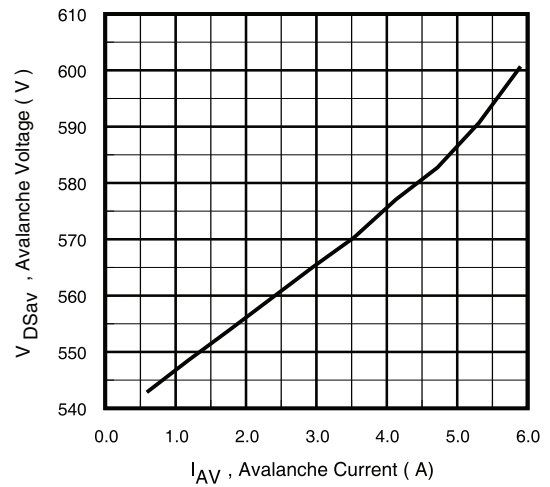


Fig. 12d - Typical Drain-to-Source Voltage vs. Avalanche Current

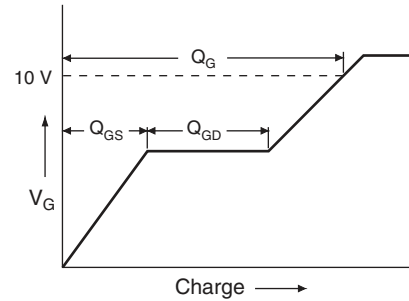


Fig. 13a - Basic Gate Charge Waveform

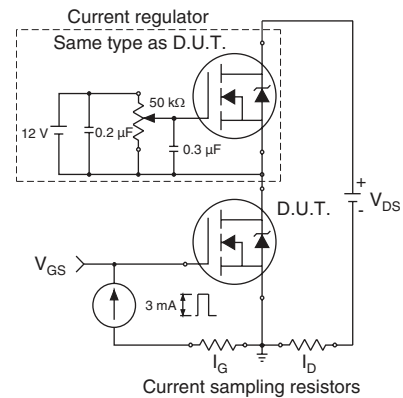
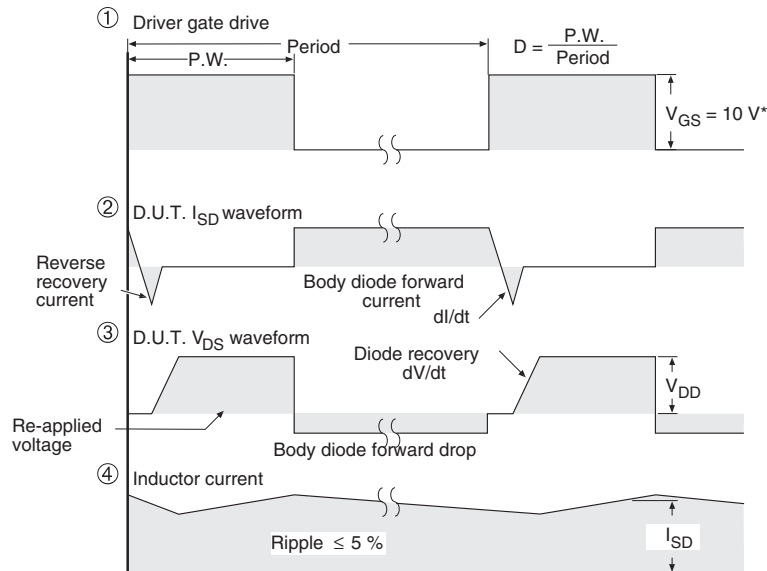
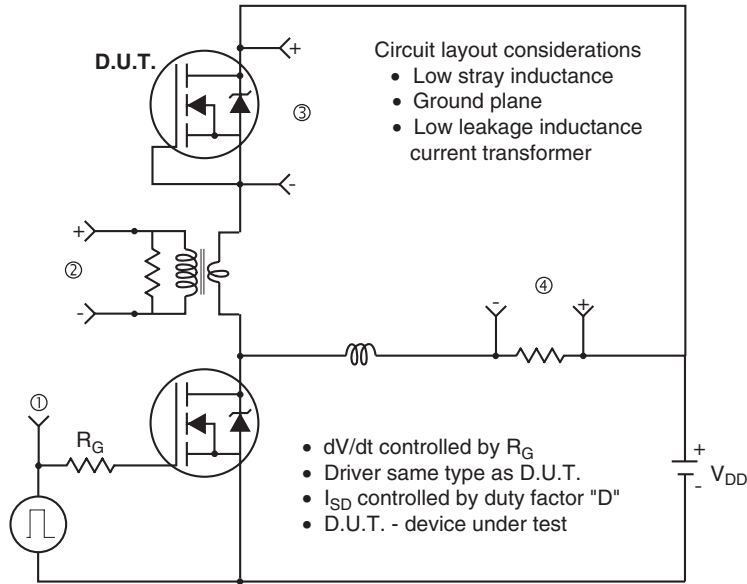


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit



* $V_{GS} = 5\text{ V}$ for logic level devices

Fig. 14 - For N-Channel

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